TOSHIBA CMOS Integrated Circuit Silicon Monolithic

# **JT6N38S**

#### Single-Chip System LSI for RFID Card

The JT6N38S is a system LSI for radio frequency identification (RFID) wireless cards. The JT6N38S incorporates an analog circuit, a data processing circuit and data memory in a single chip.

#### **Features**

- High-noise-resistant PSK modulation:
   binary phase-shift keying (BPSK) for both reader-to-RFID and RFID-to-reader transmission.
- Start-stop synchronization and half-duplex transmission: with parity, 1 stop bit
- High-efficiency power generation circuit using electromagnetic induction: battery less operation, full-wave rectifier circuit, shunt regulator
- Data processing logic circuit: digital PLL, security circuit
- High-reliablity E<sup>2</sup>PROM: 4 Kbits

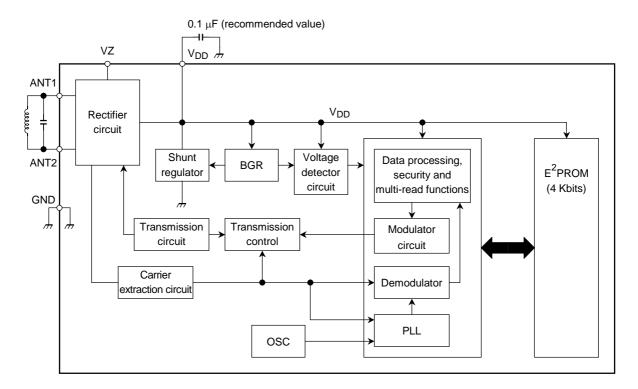
Maximum write time: 7 ms (16-byte batch write)

Overwrite: 100,000 times Data retention: 10 years

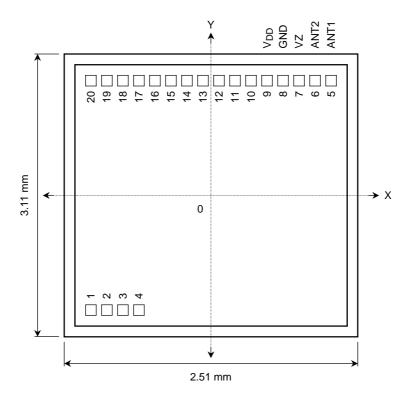
- Selectable receive carrier frequency: 120 kHz to 500 kHz (when external antenna circuit is used)
- Serial transmitter circuit (for active PSK): long-distance communication supported
- · Programmable security circuit: security level can be set
- High-speed transfer rate of 25 kbps: 1/16 of receive carrier frequency = 400 kHz
- High-speed multi-read of 32 IDs per second: when receive carrier frequency = 400 kHz (ID only read)
- Supplied as chips or on wafer

Chip thickness: 175 µm (typ.)

### System Block Diagram



#### **Pad Allocation**



## **Pad Coordinates**

Pad No.	Pad Name	X-Coordinate (μm)	Y-Coordinate (μm)
1	Test pin	-989	-1419
2	Test pin	-849	-1419
3	Test pin	-709	-1419
4	Test pin	-569	-1419
5	ANT1	1108	1419
6	ANT2	968	1419
7	Test pin	828	1419
8	GND	688	1419
9	$V_{DD}$	548	1419
10	Test pin	408	1419
11	Test pin	268	1419
12	Test pin	128	1419
13	Test pin	-12	1419
14	Test pin	-152	1419
15	Test pin	-292	1419
16	Test pin	-432	1419
17	Test pin	-572	1419
18	Test pin	-712	1419
19	Test pin	-852	1419
20	Test pin	-1000	1419

Note: Values for X-and Y-coordinates are pad center values.

## **Pin Functions**

Pin No.	Symbol	Function
5	ANT1	Rectifier diode input, antenna connection pin 1
6	ANT2	Rectifier diode input (carrier extraction input side), antenna connection pin 2
7	VZ	Bridge diode output for rectification
8	GND	GND-internal circuit voltage reference
9	$V_{DD}$	Power supply for regulator voltage and internal circuits
1~4, 10~20	_	LSI test pins

## **LSI External Specifications**

Parameter	Specifications				
Power supply	Battery less-externally supplied by electromagnetic induction				
Coupling type	Electromagnetic induction				
Power feed frequency	120 kHz~500 kHz Note: External devices such as antenna and capacitors must be selected.				
Communications method	Receive: PSK, Transmission: PSK (carrier frequency is half the power feeding frequency)				
Transfer speed	1/16 of power feeding frequency				
Transfer method	Half-duplex start-stop synchronization transmission (with parity, 1 stop bit)				
Memory size	4-Kbit E <sup>2</sup> PROM (512 bits are used as security area.)				
Write time	7 ms max (for batch write of 16 bytes)				
	Key checking and access level control by hardware				
	Incorporates six access keys (6-byte key and 2-byte status).				
Control circuit	Using access keys, read-only or write/read privilege can be set independently for each 64-byte area (programmable security).				
	Block write or read in units of 16 bytes using an access key and physical address.				
	Controls multi-read using Multi-Read command.				
Multi-read	32 reads/s (typical value with power feed frequency of 400 kHz)				
Operating temperature	-20°C~+85°C				

#### **Functions and Specifications of the Core Block**

The JT6N38S is comprised of the following: an RF analog block for power generation, carrier extraction and regulation, and a digital block for data modulation, demodulation and data processing an  $\rm E^2PROM$  for data storage.

#### 1. Analog Block

(1) Rectifier circuit

Receives radio wave via the (external) antenna circuit and generates DC power for operating internal circuits with full-wave rectification.

(2) Shunt regulator

Maintains the voltage generated by the rectifier circuit at a fixed voltage, 3.1 V (typ.). The digital circuits and E<sup>2</sup>PROM operate using the voltage supplied by the shunt regulator. The shunt regulator also protects internal circuits from the effects of strong electric fields.

(3) Carrier extraction circuit

Shapes the PSK-processed received carrier in to a square wave which is then input to the logic circuits for demodulation.

(4) Oscillation circuit (OSC)

Generates a clock for the digital PLL in the logic block.

(Oscillation frequency range: 8 MHz~12 MHz)

(5) Transmitter circuit (serial transmitter circuit for active PSK)

Powerfully modulates transmission by switching the line between the rectifier circuit and the shunt regulator. The switching is performed at half the received carrier frequency. That is, the transmission carrier frequency is half the received carrier frequency.

Note that when the rectifier circuit and the shunt regulator are left open, protection is performed for the bridge rectifier circuit so that the voltage at the bridge rectifier circuit is up to three times the remaining voltage of the shunt regulator.

(6) Voltage detector

Supports three types of voltage detector circuit for initializing the system and enabling/disabling  $E^2$ PROM writing. As a result, operation is always stable.

#### 2. Digital Block

(1) Demodulator

Converts the PSK signal shaped by the carrier extraction circuit of the analog block into binary data.

(2) Digital PLL

Compares the frequency of the oscillator circuit in the analog block with the signal shaped by the carrier extraction circuit and generates a clock with a fixed frequency for operation of the entire digital block. Using the clock the internal LSI operates in synchronize with the carrier.

(3) Data processing

Processes data according to the commands received. Processes include parity check, E<sup>2</sup>PROM write and read, and reset of the entire LSI.

(4) Security logic

Six keys can be set simultaneously using the security area allocated to the  $E^2PROM$ . Using the keys, write/read, read or no access can be set in units of 64-byte blocks (obtained by dividing  $E^2PROM$  memory area by four). (For example, with key A, read/write for a particular block can be set, while with key B, read/write for all block can be set.)

(5) Status reply

Replies to a command from the R/W consist of the status followed by data. The status represents, the internal status of the LSI to the R/W. If the LSI status is normal, status data 00H is inserted at the beginning (without any parity, start or end bits) followed by the data. If the LSI status is abnormal, no data follows and only the status indicating the abnormality is sent. The bit corresponding to each abnormality condition which has occurred is set to 1 in the status field.

(6) Multi-read

Multi-read is a function used for reading multiple RFIDs in the communications area using the same reader/writer (R/W). An RFID (LSI) generates a random number internally using the Multi-Read command transmitted by the R/W. The RFID replies using the response timing determined by the corresponding time slot. Thus, replies from the different RFIDs will not conflict, enabling data to be received properly by the R/W.

Note: Depending on the reading environment, the ability to read all the data may fluctuate . In some cases, some data may be left unread (since it cannot be undetected). Toshiba recommend the use of an additional chip with a detection function other than the multi-read function.

#### **Electrical Characteristics**

#### 1. Ratings

Parameter	Symbol	Operating Rating	Unit
Input current (between ANT1 → GND → ANT2)	I <sub>ANT</sub>	DC30	mA
Operating temperature range	T <sub>opr</sub>	-20~+85	°C
Storage temperature range	T <sub>stg</sub>	−50 <b>~</b> +150	°C

<sup>\*:</sup> Unless otherwise specified, the specifications are within the above operating temperature range.

## 2. DC Characteristics (Ta = $-20 \sim +85$ °C)

Parameter	rameter Symbol Test Circuit Description		Min	Тур.	Max	Unit	
Minimum operating voltage 1	V <sub>DD</sub> (min)	_	Minimum operating voltage excluding memory write (Voltage check pin is V <sub>DD</sub> .)	_	2.0	2.2	V
Minimum operating voltage 2	V <sub>DD</sub> (eew)	_	Minimum operating voltage including memory write (Voltage check pin is V <sub>DD</sub> .)	_	2.7	2.9	V
Operating current dissipation 1	I <sub>DDopr1</sub>	_	Current dissipation for operations excluding memory write (V <sub>DD</sub> = 2.5 V)	_	400	600	μА
Operating current dissipation 2	I <sub>DDopr2</sub>	_	Current dissipation for all operations including memory write (V <sub>DD</sub> = 2.9 V)	_	600	900	μА
Reply Peak Voltage	V <sub>psk</sub>	_	Peak voltage of VZ pin at reply (V <sub>DD</sub> as reference) times		2.5		

## 3. Operation Characteristics ( $Ta = -20 \sim +85$ °C)

Parameter	Symbol	Test Circuit	Description	Min	Тур.	Max	Unit
Receive carrier frequency	f <sub>crr</sub>	_	Carrier frequency at which operation is possible 120 — 500				kHz
Reply carrier frequency	f <sub>psk</sub>	_	Carrier frequency at reply	fcrr × 1/2		)	kHz
Transfer rate	_	_	Transfer speed	fcrr × 1/16		6	bps
Receive 1-bit frequency	_	_	Receiving carrier frequency per bit	16			Cycles
Reply 1-bit frequency	_	_	Reply carrier frequency per bit	8			Cycles
E <sup>2</sup> PROM write time	t <sub>pw</sub>	_	_	_	_	7	ms
E <sup>2</sup> PROM overwrite time	_	_	_	10 <sup>5</sup>	_	_	No. of times
E <sup>2</sup> PROM data hold time	_	_	_ 10		_	Years	

#### **Memory Map**

Page No	16-Byte Block		Page No	16-Byte Block		
00H	ATR data		01H	Key 0010	Key 0011	
02H	Key 0100	Key 0101	03H	Key 0110	Key 0111	
04H	Any	data	05H	Any data		
06H	Any	data	07H	Any data		
08H	Any	data	09H	Any data		
0AH	Any	data	0BH	Any data		
0CH	Any	data	0DH	Any data		
0EH	Any data		0FH	Any data		
10H	Any data		11H	Any data		
12H	Any data		13H	Any data		
14H	Any data		15H	Any data		
16H	Any data		17H	Any data		
18H	Any data		19H	Any data		
1AH	Any data		1BH	Any data		
1CH	Any data		1DH	Any data		
1EH	Any data		1FH	Any data		

Note 1: ATR: Answer to Reset. The LSI sends back the ATR data after receiving a reset command or self reset.

Note 2: Using the keys at 01H to 03H, access privileges can be set for the 64-byte blocks (enclosed by bold lines) from 04H to 1FH. A key area consists of 8 bytes.

Note 3: Write to E<sup>2</sup>PROM is performed in units of 16 bytes to addresses matching the page numbers above.

The advantage of using this LSI is that it can be supplied as a single LSI for RFID allowing the user to configure peripherals (e.g. antennae, and reader/writers) so as to develop the desired system. However, because the peripheral environment may be highly user-specific, incompatibilities between the LSI and the user-configured environment (communications failures) may occur. Please carry out sufficient research before using this LSI.

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